



## Test Report

**Report No. :** CQASZ20250400929E-01  
**Applicant:** Shenzhen Buzz Tech CO.,LTD  
**Address of Applicant:** 10th Floor, Guang Chang Bldg, 74#, BaoMin 1st Rd, Bao An Shenzhen, Guangdong, China

**Equipment Under Test (EUT):**

**Product:** Smart glasses  
**Model No.:** M01, M02  
**Test Model No.:** M01  
**Brand Name:** N/A  
**FCC ID:** 2AGFW-M01  
**Standards:** 47 CFR Part 15, Subpart C  
KDB558074 D01 15.247 Meas Guidance v05r02  
ANSI C63.10:2013  
**Date of Receipt:** 2025-04-25  
**Date of Test:** 2025-04-25 to 2025-05-21  
**Date of Issue:** 2025-05-22  
**Test Result :** PASS\*

\*In the configuration tested, the EUT complied with the standards specified above.

**Tested By:** lewis zhou

( Lewis Zhou )

**Reviewed By:** Timo Lei

( Timo Lei )

**Approved By:** Jack Ai

( Jack Ai )



## 1 Version

### Revision History Of Report

Report No.	Version	Description	Issue Date
CQASZ20250400929E-01	Rev.01	Initial report	2025-05-22

## 2 Test Summary

Test Item	Test Requirement	Test method	Result
Antenna Requirement	47 CFR Part 15.203	/	PASS
AC Power Line Conducted Emission	47 CFR Part 15, Subpart C Section 15.207	ANSI C63.10-2013	PASS
Conducted Peak Output Power	47 CFR Part 15.247	ANSI C63.10-2013	PASS
20dB Occupied Bandwidth	47 CFR Part 15.247	ANSI C63.10-2013	PASS
Carrier Frequencies Separation	47 CFR Part 15.247	ANSI C63.10-2013	PASS
Hopping Channel Number	47 CFR Part 15.247	ANSI C63.10-2013	PASS
Dwell Time	47 CFR Part 15.247	ANSI C63.10-2013	PASS
Pseudorandom Frequency Hopping Sequence	47 CFR Part 15.247	ANSI C63.10-2013	PASS
Band-edge for RF Conducted Emissions	47 CFR Part 15.247	ANSI C63.10-2013	PASS
RF Conducted Spurious Emissions	47 CFR Part 15.247	ANSI C63.10-2013	PASS
Radiated Spurious emissions	47 CFR Part 15.209	ANSI C63.10-2013	PASS
Restricted bands around fundamental frequency (Radiated Emission)	47 CFR Part 15.205/15.209	ANSI C63.10-2013	PASS

Remark:

The tested sample(s) and the sample information are provided by the client.

Tx: In this whole report Tx (or tx) means Transmitter.

Rx: In this whole report Rx (or rx) means Receiver.

RF: In this whole report RF means Radiated Frequency.

CH: In this whole report CH means channel.

Volt: In this whole report Volt means Voltage.

Temp: In this whole report Temp means Temperature.

Humid: In this whole report Humid means humidity.

Press: In this whole report Press means Pressure.

N/A: In this whole report not application

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## 4 General Information

### 4.1 Client Information

Applicant:	Shenzhen Buzz Tech CO.,LTD
Address of Applicant:	10th Floor, Guang Chang Bldg, 74#, BaoMin 1st Rd, Bao An Shenzhen, Guangdong, China
Manufacturer:	Shenzhen Buzz Tech CO.,LTD
Address of Manufacturer:	10th Floor, Guang Chang Bldg, 74#, BaoMin 1st Rd, Bao An Shenzhen, Guangdong, China
Factory:	Shenzhen Buzz Tech CO.,LTD
Address of Factory:	10th Floor, Guang Chang Bldg, 74#, BaoMin 1st Rd, Bao An Shenzhen, Guangdong, China

### 4.2 General Description of EUT

Product Name:	Smart glasses
Model No.:	M01, M02
Test Model No.:	M01
Trade Mark:	N/A
Software Version:	V1.0
Hardware Version:	V1.0
Operation Frequency:	2402MHz~2480MHz
Bluetooth Version:	V5.0
Modulation Technique:	Frequency Hopping Spread Spectrum(FHSS)
Modulation Type:	GFSK, $\pi/4$ DQPSK, 8DPSK
Transfer Rate:	1Mbps/2Mbps/3Mbps
Number of Channel:	79
Hopping Channel Type:	Adaptive Frequency Hopping systems
Product Type:	<input type="checkbox"/> Mobile <input checked="" type="checkbox"/> Portable <input type="checkbox"/> Fix Location
Test Software of EUT:	FCC_assist1.0.4
Antenna Type:	Internal antenna
Antenna Gain:	0dBi
Power Supply:	Li-ion battery: DC 3.8V 220mAh/0.84Wh, Charge by DC 5V
Simultaneous Transmission	<input checked="" type="checkbox"/> Simultaneous TX is supported and evaluated in this report. <input type="checkbox"/> Simultaneous TX is not supported.

Note:

Model No.: M01, M02

Only the model M01 was tested, their electrical circuit design, layout, components used and internal wiring are identical, only the color of the product is different, so the model name is also different.

Operation Frequency each of channel							
Channel	Frequency	Channel	Frequency	Channel	Frequency	Channel	Frequency
0	2402MHz	20	2422MHz	40	2442MHz	60	2462MHz
1	2403MHz	21	2423MHz	41	2443MHz	61	2463MHz
2	2404MHz	22	2424MHz	42	2444MHz	62	2464MHz
3	2405MHz	23	2425MHz	43	2445MHz	63	2465MHz
4	2406MHz	24	2426MHz	44	2446MHz	64	2466MHz
5	2407MHz	25	2427MHz	45	2447MHz	65	2467MHz
6	2408MHz	26	2428MHz	46	2448MHz	66	2468MHz
7	2409MHz	27	2429MHz	47	2449MHz	67	2469MHz
8	2410MHz	28	2430MHz	48	2450MHz	68	2470MHz
9	2411MHz	29	2431MHz	49	2451MHz	69	2471MHz
10	2412MHz	30	2432MHz	50	2452MHz	70	2472MHz
11	2413MHz	31	2433MHz	51	2453MHz	71	2473MHz
12	2414MHz	32	2434MHz	52	2454MHz	72	2474MHz
13	2415MHz	33	2435MHz	53	2455MHz	73	2475MHz
14	2416MHz	34	2436MHz	54	2456MHz	74	2476MHz
15	2417MHz	35	2437MHz	55	2457MHz	75	2477MHz
16	2418MHz	36	2438MHz	56	2458MHz	76	2478MHz
17	2419MHz	37	2439MHz	57	2459MHz	77	2479MHz
18	2420MHz	38	2440MHz	58	2460MHz	78	2480MHz
19	2421MHz	39	2441MHz	59	2461MHz		

**Note:**

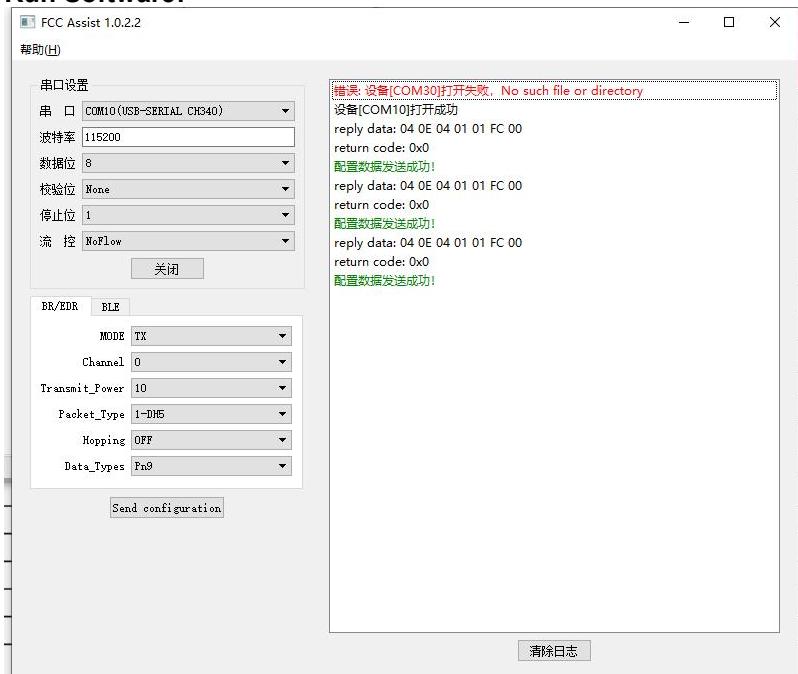
In section 15.31(m), regards to the operating frequency range over 10 MHz, the Lowest frequency, the middle frequency, and the highest frequency of channel were selected to perform the test, and the selected channel see below:

Channel	Frequency
The Lowest channel	2402MHz
The Middle channel	2441MHz
The Highest channel	2480MHz

### 4.3 Additional Instructions

<b>EUT Test Software Settings:</b>		
Mode:	<input checked="" type="checkbox"/> Special software is used. <input type="checkbox"/> Through engineering command into the engineering mode. engineering command: *###3646633#**#	
EUT Power level:	Class 10	
Use test software to set the lowest frequency, the middle frequency and the highest frequency keep transmitting of the EUT.		
Mode	Channel	Frequency(MHz)
DH1/DH3/DH5	CH0	2402
	CH39	2441
	CH78	2480
2DH1/2DH3/2DH5	CH0	2402
	CH39	2441
	CH78	2480
3DH1/3DH3/3DH5	CH0	2402
	CH39	2441
	CH78	2480

#### Run Software:



#### 4.4 Test Environment

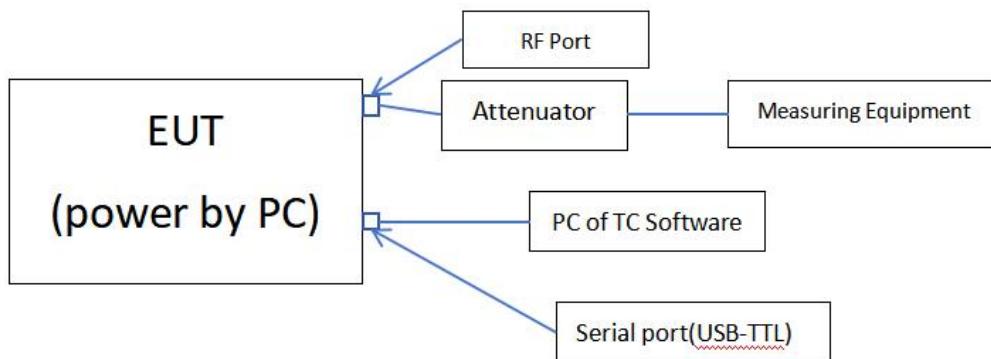
Operating Environment:	
Temperature:	25 °C
Humidity:	54% RH
Atmospheric Pressure:	1009mbar
Test Mode:	Use test software to set the lowest frequency, the middle frequency and the highest frequency keep transmitting of the EUT.

#### 4.5 Description of Support Units

The EUT has been tested with associated equipment below.

Description	Manufacturer	Model No.	Remark	Supplied
Adapter	MI	/	/	CQA

#### 4.6 Test configuration



## 4.7 Statement of the measurement uncertainty

The data and results referenced in this document are true and accurate.

The reader is cautioned that there may be errors within the calibration limits of the equipment and facilities.

The measurement uncertainty was calculated for all measurements listed in this test report acc. to CISPR 16 - 4 „Specification for radio disturbance and immunity measuring apparatus and methods – Part 4: Uncertainty in EMC Measurements“ and is documented in the **Shenzhen Huaxia Testing Technology Co., Ltd.** quality system acc. to DIN EN ISO/IEC 17025.

Furthermore, component and process variability of devices similar to that tested may result in additional deviation. The manufacturer has the sole responsibility of continued compliance of the device.

Hereafter the best measurement capability for CQA laboratory is reported:

No.	Item	Uncertainty
1	Radiated Emission (Below 1GHz)	5.12dB
2	Radiated Emission (Above 1GHz)	4.60dB
3	Conducted Disturbance (0.15~30MHz)	3.34dB
4	Radio Frequency	$3 \times 10^{-8}$
5	Duty cycle	0.6 %
6	Occupied Bandwidth	1.1%
7	RF conducted power	0.86dB
8	RF power density	0.74
9	Conducted Spurious emissions	0.86dB
10	Temperature test	0.8 °C
11	Humidity test	2.0%
12	Supply voltages	0.5 %
13	Frequency Error	5.5 Hz

## **4.8 Test Location**

All tests were performed at:

Shenzhen Huaxia Testing Technology Co., Ltd.

1F., Block A of Tongsheng Technology Building, Huahui Road, Dalang Street, Longhua District, Shenzhen, China

## **4.9 Test Facility**

The test facility is recognized, certified, or accredited by the following organizations:

**IC Registration No.: 22984-1**

The 3m Semi-anechoic chamber of Shenzhen Huaxia Testing Technology Co., Ltd. has been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing

The test facility is recognized, certified, or accredited by the following organizations:

- CNAS (No. CNAS L5785)**

CNAS has accredited Shenzhen Huaxia Testing Technology Co., Ltd. Shenzhen Branch EMC Lab to ISO/IEC 17025:2005 General Requirements for the Competence of Testing and Calibration Laboratories (CNAS-CL01 Accreditation Criteria for the Competence of Testing and Calibration Laboratories) for the competence in the field of testing.

- A2LA (Certificate No. 4742.01)**

Shenzhen Huaxia Testing Technology Co., Ltd., Shenzhen EMC Laboratory is accredited by the American Association for Laboratory Accreditation(A2LA). Certificate No. 4742.01.

- FCC Registration No.: 522263**

Shenzhen Huaxia Testing Technology Co., Ltd., Shenzhen EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration No.:522263

## **4.10 Abnormalities from Standard Conditions**

None.

## **4.11 Other Information Requested by the Customer**

None.

## 4.12 Equipment List

Test Equipment	Manufacturer	Model No.	Instrument No.	Calibration Date	Calibration Due Date
EMI Test Receiver	R&S	ESR7	CQA-005	2024/9/2	2025/9/1
Spectrum analyzer	R&S	FSU26	CQA-038	2024/9/2	2025/9/1
Spectrum analyzer	R&S	FSU40	CQA-075	2024/9/2	2025/9/1
Preamplifier	MITEQ	AFS4-00010300-18-10P-4	CQA-035	2024/9/2	2025/9/1
Preamplifier	MITEQ	AMF-6D-02001800-29-20P	CQA-036	2024/9/2	2025/9/1
Preamplifier	EMCI	EMC184055SE	CQA-089	2024/9/2	2025/9/1
Loop antenna	Schwarzbeck	FMZB1516	CQA-060	2023/9/8	2026/9/7
Bilog Antenna	R&S	HL562	CQA-011	2023/11/01	2026/10/31
Horn Antenna	R&S	HF906	CQA-012	2023/11/01	2026/10/31
Horn Antenna	Schwarzbeck	BBHA 9170	CQA-088	2023/9/7	2026/9/6
Coaxial Cable (Above 1GHz)	CQA	N/A	C007	2024/9/2	2025/9/1
Coaxial Cable (Below 1GHz)	CQA	N/A	C013	2024/9/2	2025/9/1
Antenna Connector	CQA	RFC-01	CQA-080	2024/9/2	2025/9/1
RF cable(9KHz~40GHz)	CQA	RF-01	CQA-079	2024/9/2	2025/9/1
Power meter	R&S	NRVD	CQA-029	2024/9/2	2025/9/1
Power divider	MIDWEST	PWD-2533-02-SMA-79	CQA-067	2024/9/2	2025/9/1
EMI Test Receiver	R&S	ESR7	CQA-005	2024/9/2	2025/9/1
LISN	R&S	ENV216	CQA-003	2024/9/2	2025/9/1
Coaxial cable	CQA	N/A	CQA-C009	2024/9/2	2025/9/1
DC power	KEYSIGHT	E3631A	CQA-028	2024/9/2	2025/9/1

Test software:

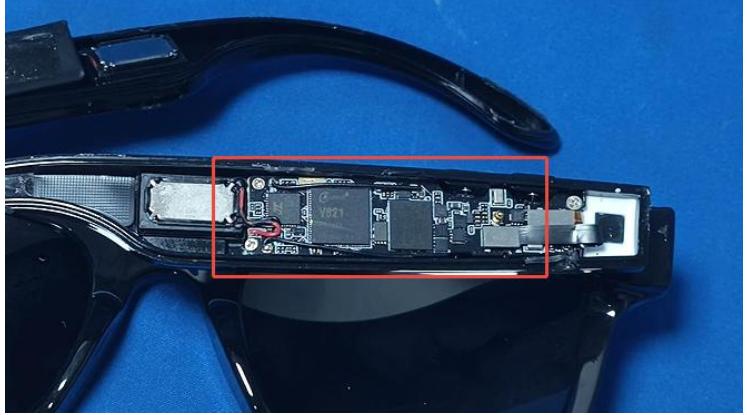
	Manufacturer	Software brand	Software version
Radiated Emissions test software	Tonscend	JS1120-3	Version:8
Conducted Emissions test software	Audix	e3	Version:9
RF Conducted test software	Audix	e3	V3.5.39

Note:

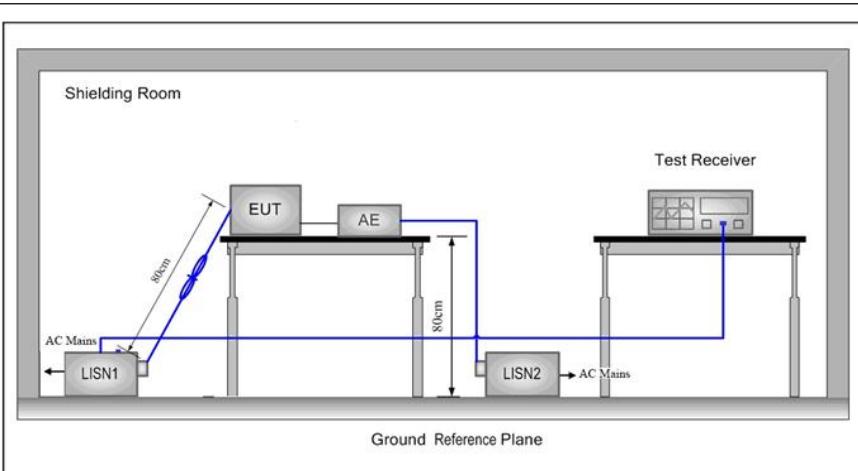
The temporary antenna connector is soldered on the PCB board in order to perform conducted tests and this temporary antenna connector is listed in the equipment list.

## 5 Test results and Measurement Data

### 5.1 Antenna Requirement

<b>Standard requirement:</b>	47 CFR Part 15C Section 15.203 /247(c)
15.203 requirement:	An intentional radiator shall be designed to ensure that no antenna other than that furnished by the responsible party shall be used with the device. The use of a permanently attached antenna or of an antenna that uses a unique coupling to the intentional radiator, the manufacturer may design the unit so that a broken antenna can be replaced by the user, but the use of a standard antenna jack or electrical connector is prohibited.
15.247(b) (4) requirement:	The conducted output power limit specified in paragraph (b) of this section is based on the use of antennas with directional gains that do not exceed 6 dBi. Except as shown in paragraph (c) of this section, if transmitting antennas of directional gain greater than 6 dBi are used, the conducted output power from the intentional radiator shall be reduced below the stated values in paragraphs (b)(1), (b)(2), and (b)(3) of this section, as appropriate, by the amount in dB that the directional gain of the antenna exceeds 6 dBi.
<b>EUT Antenna:</b>	 <p>The antenna is Internal antenna. The connection/connection type between the antenna to the EUT's antenna port is: permanently attachment. This is either permanently attachment or a unique coupling that satisfies the requirement.</p>

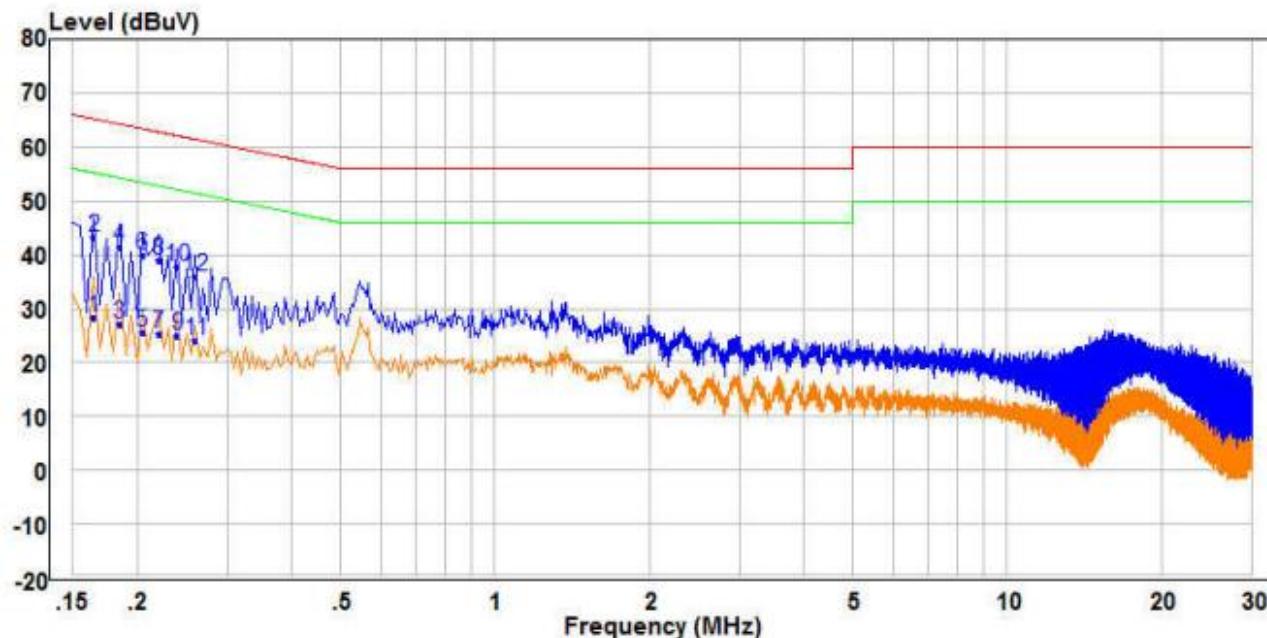
## 5.2 Conducted Emissions

Test Requirement:	47 CFR Part 15C Section 15.207		
Test Method:	ANSI C63.10: 2013		
Test Frequency Range:	150kHz to 30MHz		
Limit:	Frequency range (MHz)		Limit (dBuV)
			Quasi-peak      Average
	0.15-0.5	66 to 56*	56 to 46*
	0.5-5	56	46
		5-30	60      50
* Decreases with the logarithm of the frequency.			
Test Procedure:	<ol style="list-style-type: none"> <li>1) The mains terminal disturbance voltage test was conducted in a shielded room.</li> <li>2) The EUT was connected to AC power source through a LISN 1 (Line Impedance Stabilization Network) which provides a <math>50\Omega/50\mu\text{H} + 5\Omega</math> linear impedance. The power cables of all other units of the EUT were connected to a second LISN 2, which was bonded to the ground reference plane in the same way as the LISN 1 for the unit being measured. A multiple socket outlet strip was used to connect multiple power cables to a single LISN provided the rating of the LISN was not exceeded.</li> <li>3) The tabletop EUT was placed upon a non-metallic table 0.8m above the ground reference plane. And for floor-standing arrangement, the EUT was placed on the horizontal ground reference plane,</li> <li>4) The test was performed with a vertical ground reference plane. The rear of the EUT shall be 0.4 m from the vertical ground reference plane. The vertical ground reference plane was bonded to the horizontal ground reference plane. The LISN 1 was placed 0.8 m from the boundary of the unit under test and bonded to a ground reference plane for LISNs mounted on top of the ground reference plane. This distance was between the closest points of the LISN 1 and the EUT. All other units of the EUT and associated equipment was at least 0.8 m from the LISN 2.</li> <li>5) In order to find the maximum emission, the relative positions of equipment and all of the interface cables must be changed according to ANSI C63.10: 2013 on conducted measurement.</li> </ol>		
Test Setup:			

Exploratory Test Mode:	Non-hopping transmitting mode with all kind of modulation and all kind of data type at the lowest, middle, high channel.
Final Test Mode:	Through Pre-scan, find the DH5 of data type and GFSK modulation at the lowest channel is the worst case. Only the worst case is recorded in the report.
Test Voltage:	AC 120V/60Hz
Test Results:	Pass

**Measurement Data**

Live line:

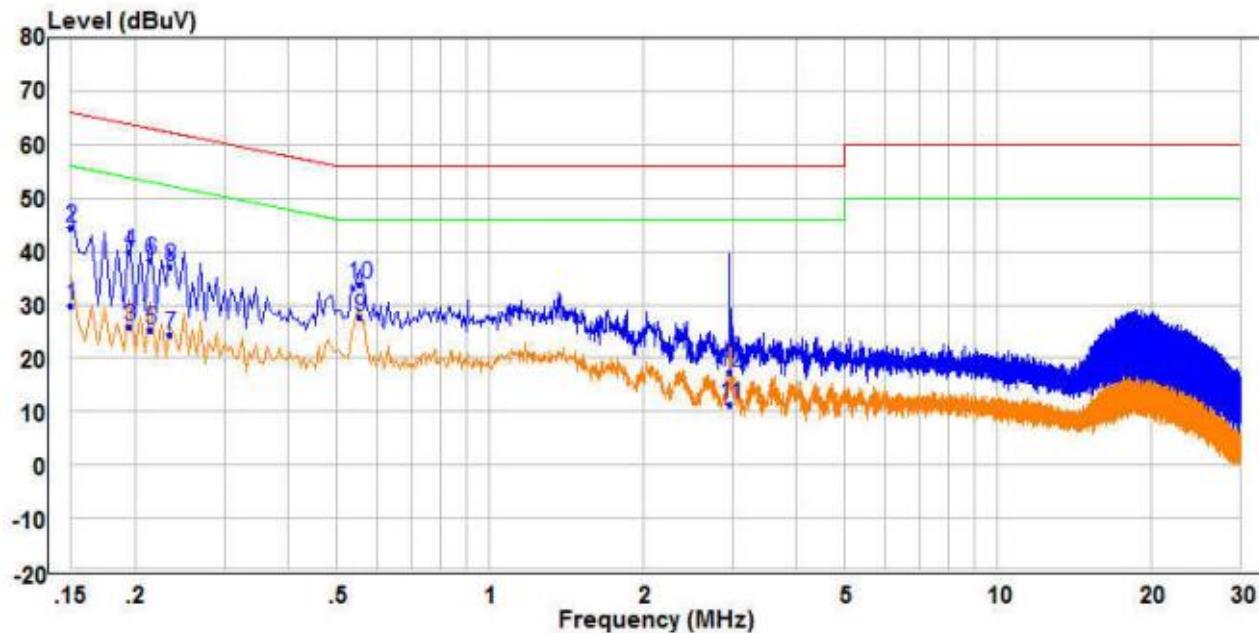


Freq	Read	Factor	Level	Limit	Over	Remark	Pol/Phase
	MHz			dBuV	dB		
1 AV	0.165	18.97	9.49	28.46	55.21	-26.75	Average
2 PP	0.165	33.67	9.49	43.16	65.21	-22.05	QP
3	0.185	17.57	9.49	27.06	54.26	-27.20	Average
4	0.185	31.88	9.49	41.37	64.26	-22.89	QP
5	0.205	16.10	9.49	25.59	53.41	-27.82	Average
6	0.205	30.35	9.49	39.84	63.41	-23.57	QP
7	0.220	15.96	9.49	25.45	52.82	-27.37	Average
8	0.220	29.63	9.49	39.12	62.82	-23.70	QP
9	0.240	15.44	9.49	24.93	52.10	-27.17	Average
10	0.240	28.33	9.49	37.82	62.10	-24.28	QP
11	0.260	14.70	9.49	24.19	51.43	-27.24	Average
12	0.260	26.42	9.49	35.91	61.43	-25.52	QP

**Remark:**

1. The following Quasi-Peak and Average measurements were performed on the EUT:
2. Final Test Level =Receiver Reading + LISN Factor + Cable Loss.
3. If the Peak value under Average limit, the Average value is not recorded in the report.

Neutral line:

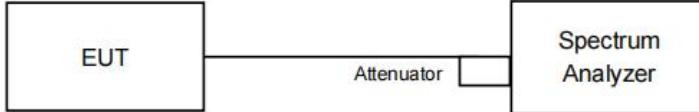


Freq	Read		Level	Limit	Over	Pol/Phase	
	MHz	dBuV		dBuV	Line	Limit	Remark
1	0.150	20.18	9.70	29.88	56.00	-26.12	Average
2 QP	0.150	34.88	9.70	44.58	66.00	-21.42	QP
3	0.195	16.40	9.62	26.02	53.82	-27.80	Average
4	0.195	30.36	9.62	39.98	63.82	-23.84	QP
5	0.215	15.83	9.59	25.42	53.01	-27.59	Average
6	0.215	28.90	9.59	38.49	63.01	-24.52	QP
7	0.235	14.95	9.56	24.51	52.27	-27.76	Average
8	0.235	27.48	9.56	37.04	62.27	-25.23	QP
9 PP	0.555	18.07	9.76	27.83	46.00	-18.17	Average
10	0.555	23.99	9.76	33.75	56.00	-22.25	QP
11	2.965	1.55	9.77	11.32	46.00	-34.68	Average
12	2.965	7.50	9.77	17.27	56.00	-38.73	QP

Remark:

1. The following Quasi-Peak and Average measurements were performed on the EUT:
2. Final Test Level =Receiver Reading + LISN Factor + Cable Loss.
3. If the Peak value under Average limit, the Average value is not recorded in the report.

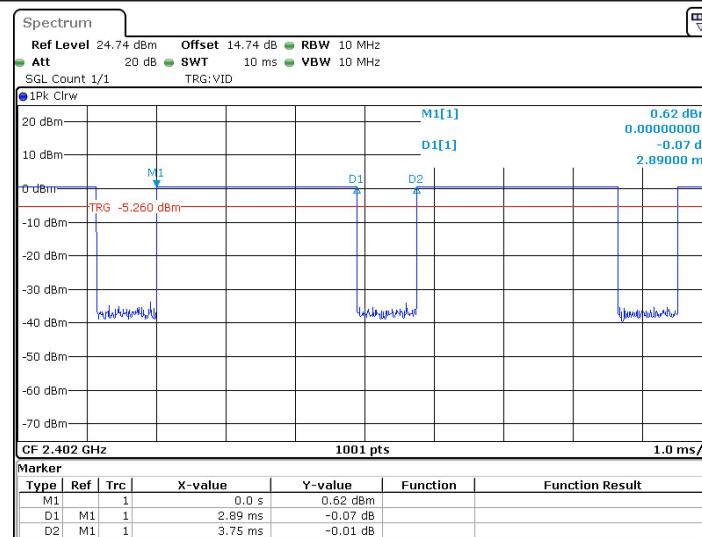
### 5.3 Conducted Peak Output Power

Test Requirement:	47 CFR Part 15C Section 15.247 (b)(1)
Test Method:	ANSI C63.10:2013
Test Setup:	<p><b>Setup for Power meter measurement method</b></p>  <p><b>Setup for Spectrum analyser measurement method</b></p>  <p><i>Remark: Offset=Cable loss+ attenuation factor.</i></p>
Limit:	30dBm
Exploratory Test Mode:	Non-hopping transmitting with all kind of modulation and all kind of data type
Final Test Mode:	Only the worst case is recorded in the report.
Test Results:	Pass

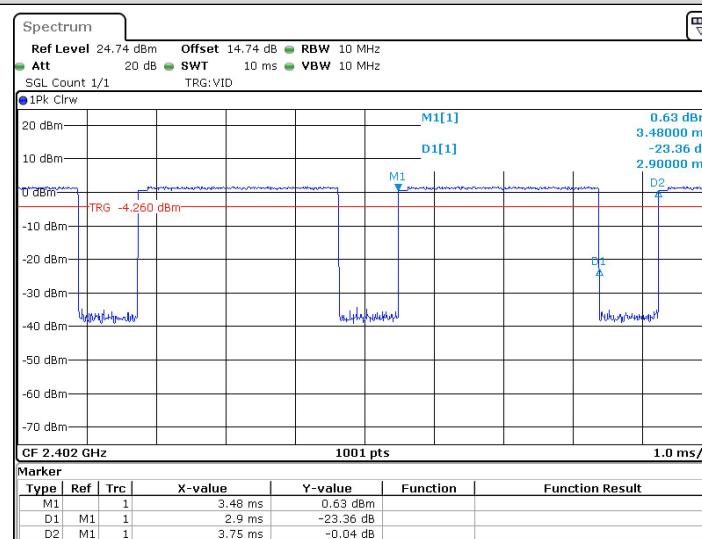
Operated Mode for Worst Duty Cycle:				
Test Mode	On time [Ton] (ms)	Period [Ttotal] ms)	Duty Cycle(%)	Average correction factor(dB)
GFSK	2.89	3.75	77.07	1.13
$\pi/4$ DQPSK	2.90	3.75	77.33	1.12
8DPSK	2.90	3.75	77.33	1.12

**Remark:**

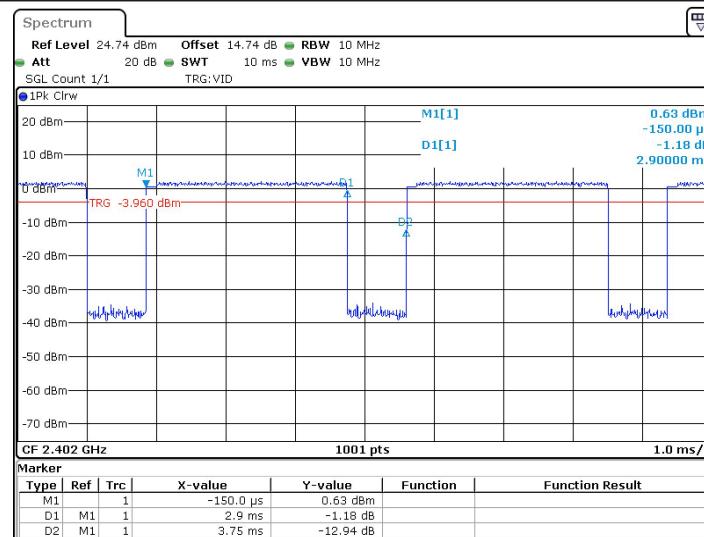
- 1) Duty cycle= On Time/ Period;
- 2) Duty Cycle factor =  $10 * \log(1/ \text{Duty cycle})$ ;

**Test Graph\_GFSK Duty Cycle:**


Date: 6.MAY.2025 15:12:43

**Test Graph\_π/4DQPSK Duty Cycle:**


Date: 6.MAY.2025 15:20:36

**Test Graph\_8DPSK Duty Cycle:**


Date: 6.MAY.2025 15:27:10

**Measurement Data**

GFSK mode			
Test channel	Peak Output Power (dBm)	Limit (dBm)	Result
Lowest	0.95	30.00	Pass
Middle	1.16	30.00	Pass
Highest	0.97	30.00	Pass

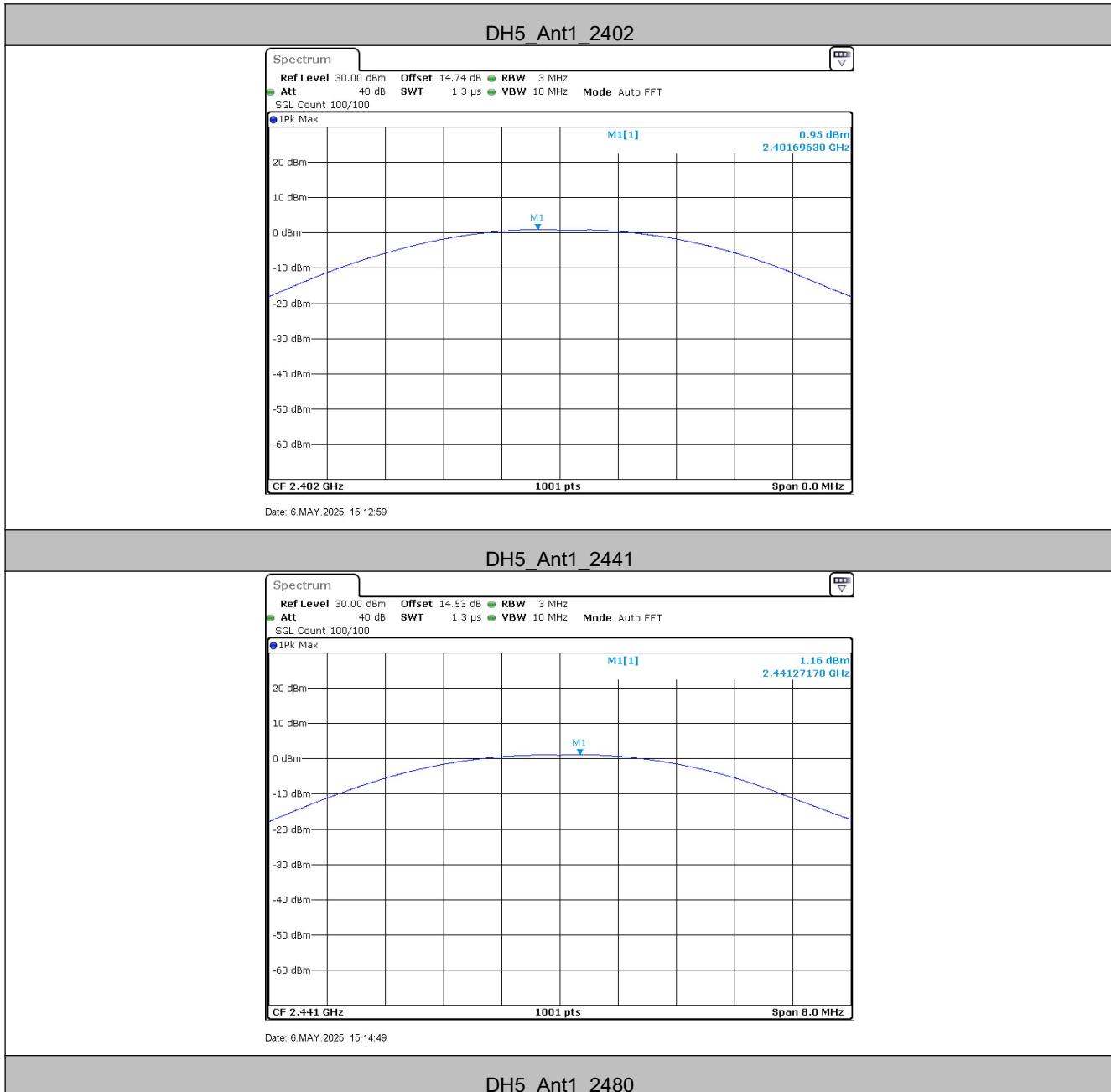
  

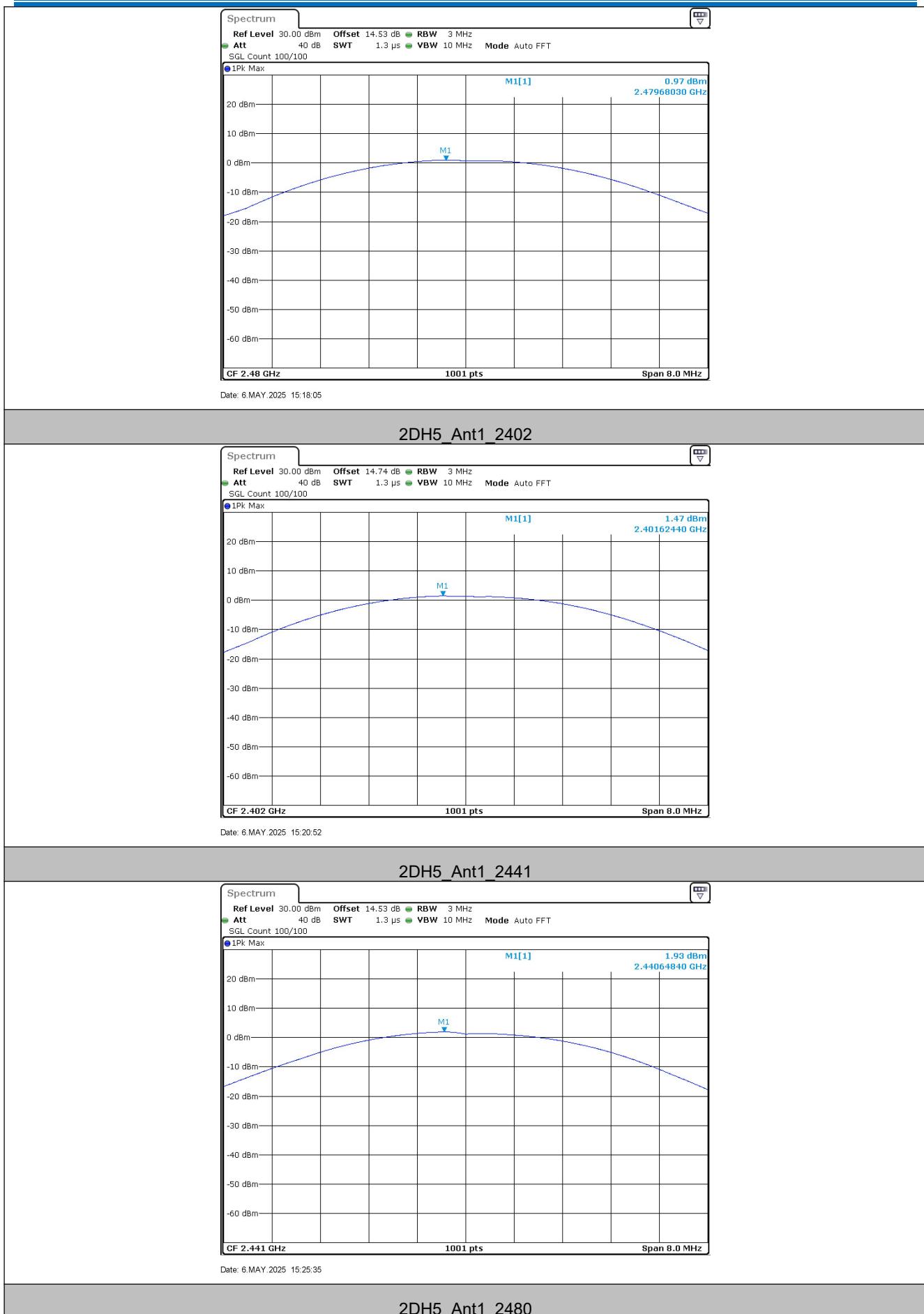
$\pi/4$ DQPSK mode			
Test channel	Peak Output Power (dBm)	Limit (dBm)	Result
Lowest	1.47	30.00	Pass
Middle	1.93	30.00	Pass
Highest	1.37	30.00	Pass

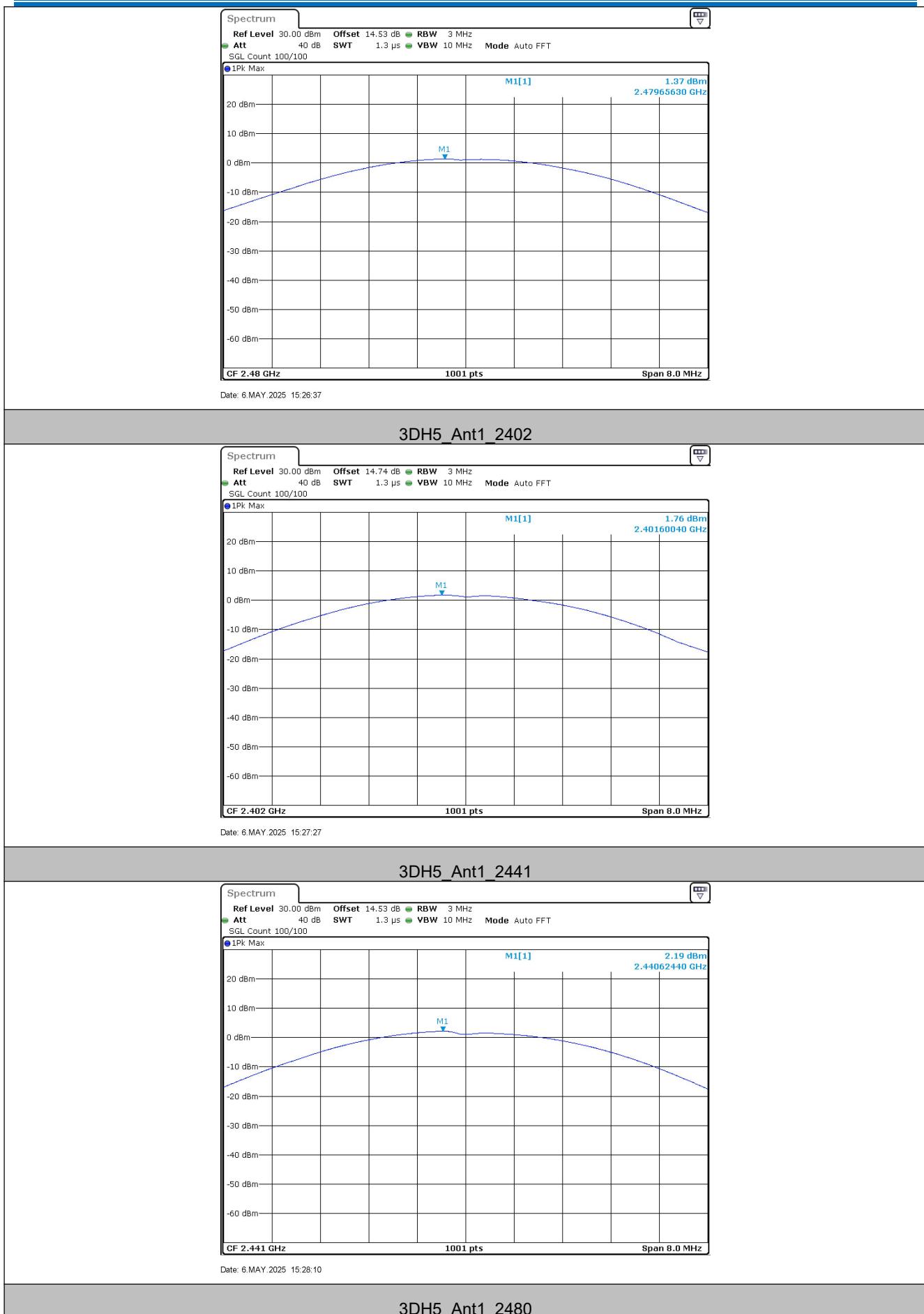
  

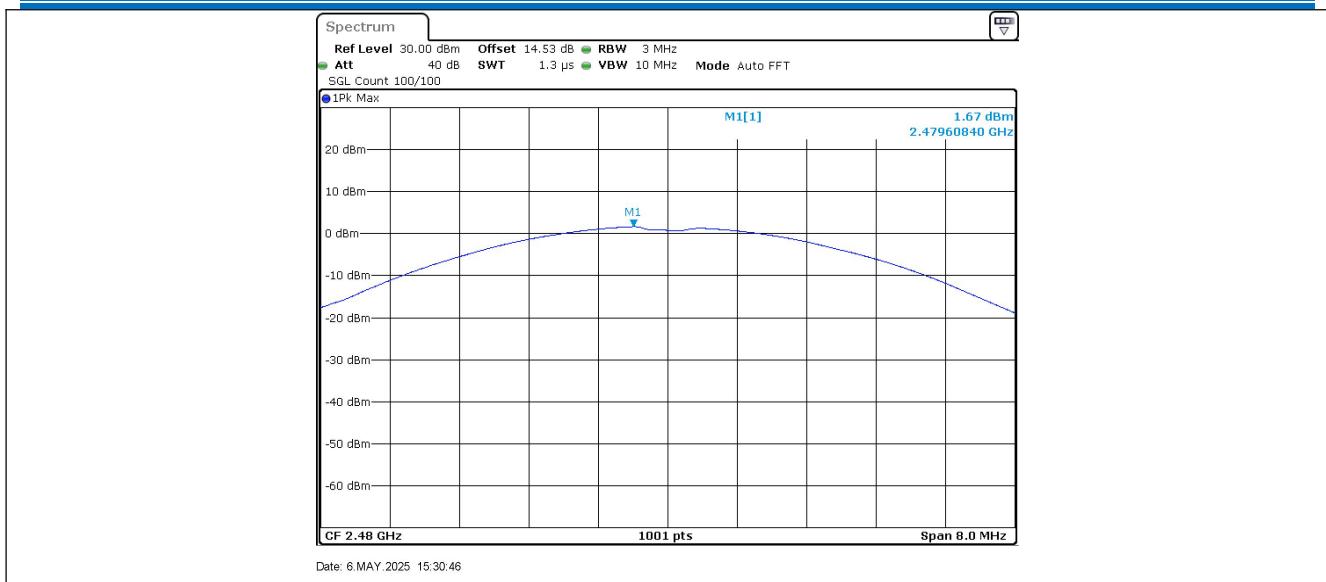
8DPSK mode			
Test channel	Peak Output Power (dBm)	Limit (dBm)	Result
Lowest	1.76	30.00	Pass
Middle	2.19	30.00	Pass
Highest	1.67	30.00	Pass

Test plot as follows:

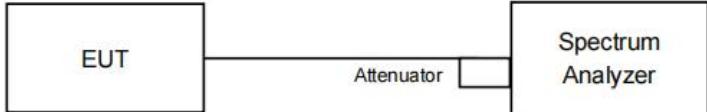






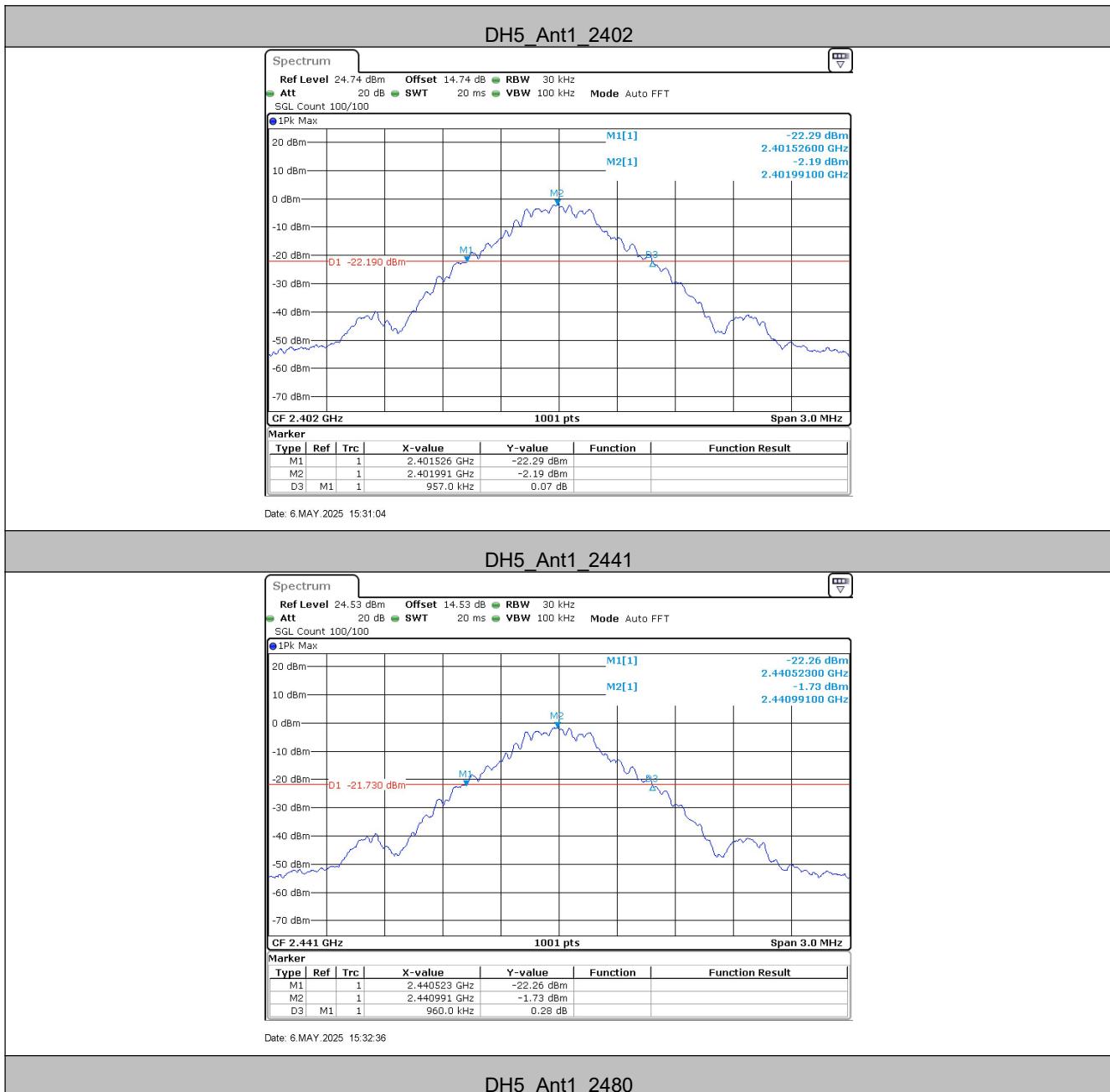


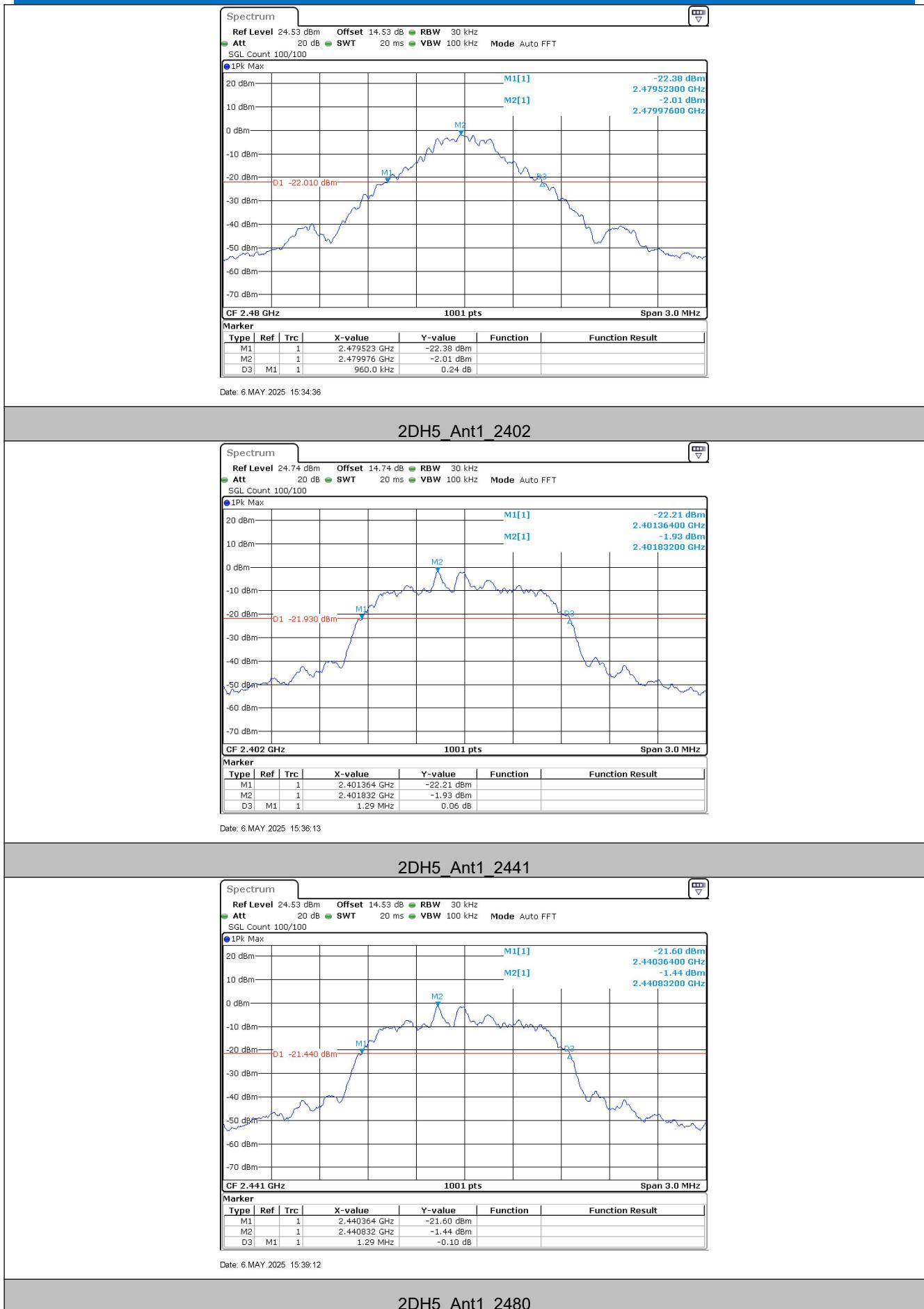
## 5.4 20dB Occupied Bandwidth

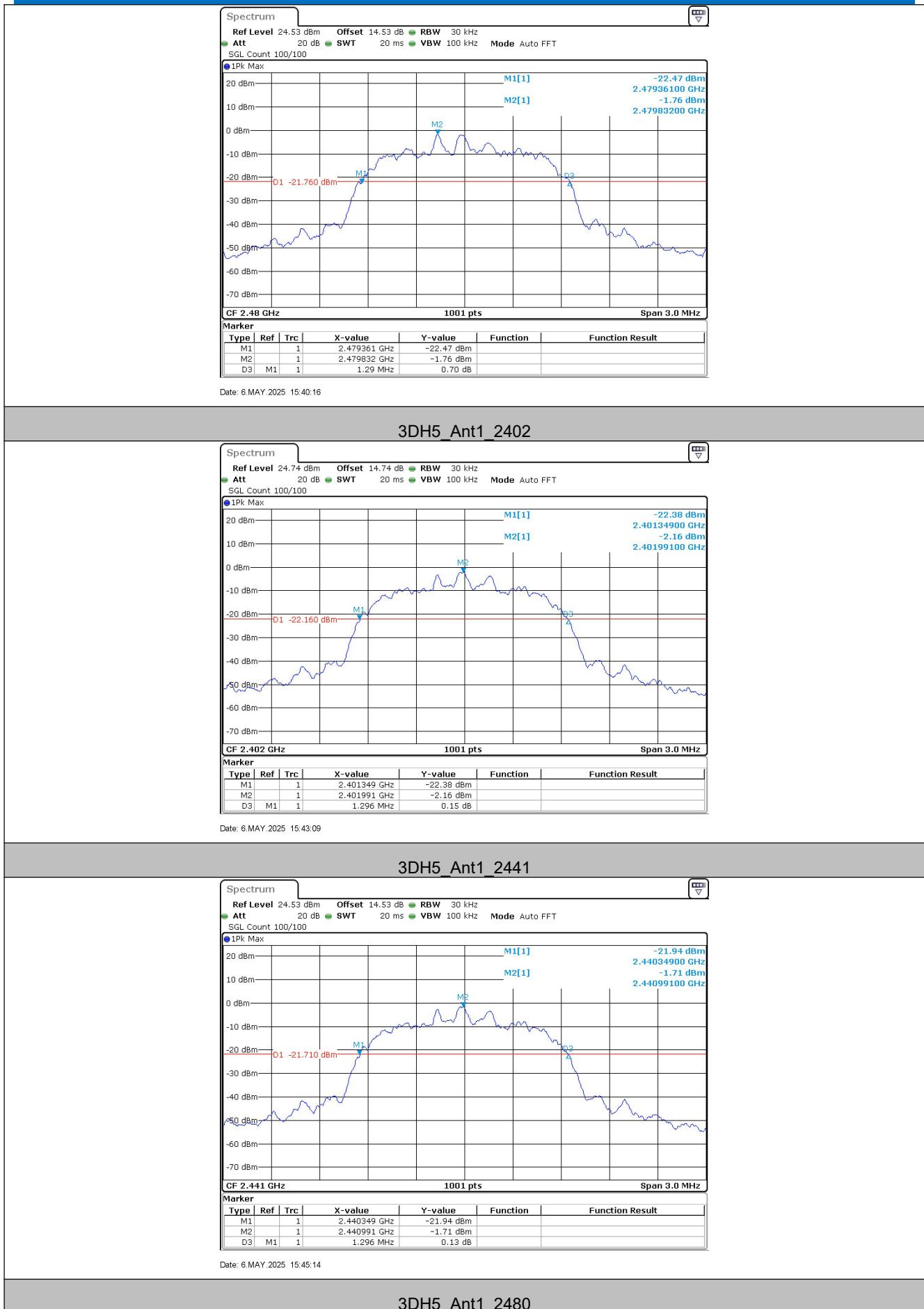
Test Requirement:	47 CFR Part 15C Section 15.247 (a)(1)	
Test Method:	ANSI C63.10:2013	
Test Setup:		<p>Remark: Offset=Cable loss+ attenuation factor.</p>
Limit:	NA	
Exploratory Test Mode:	Non-hopping transmitting with all kind of modulation and all kind of data type	
Final Test Mode:	Only the worst case is recorded in the report.	
Test Results:	Pass	

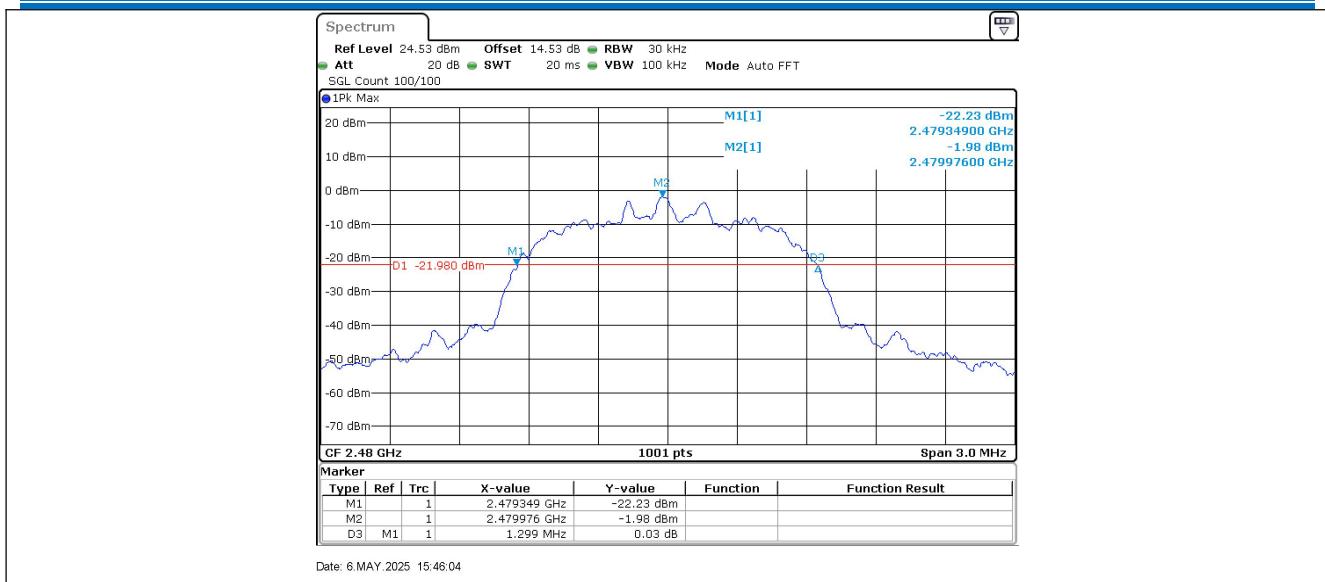
### Measurement Data

Test channel	20dB Occupy Bandwidth (MHz)		
	GFSK	$\pi/4$ DQPSK	8DPSK
Lowest	0.96	1.29	1.30
Middle	0.96	1.29	1.30
Highest	0.96	1.29	1.30

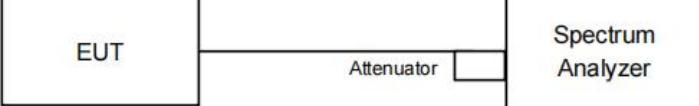
**Test plot as follows:**








## 5.5 Carrier Frequencies Separation

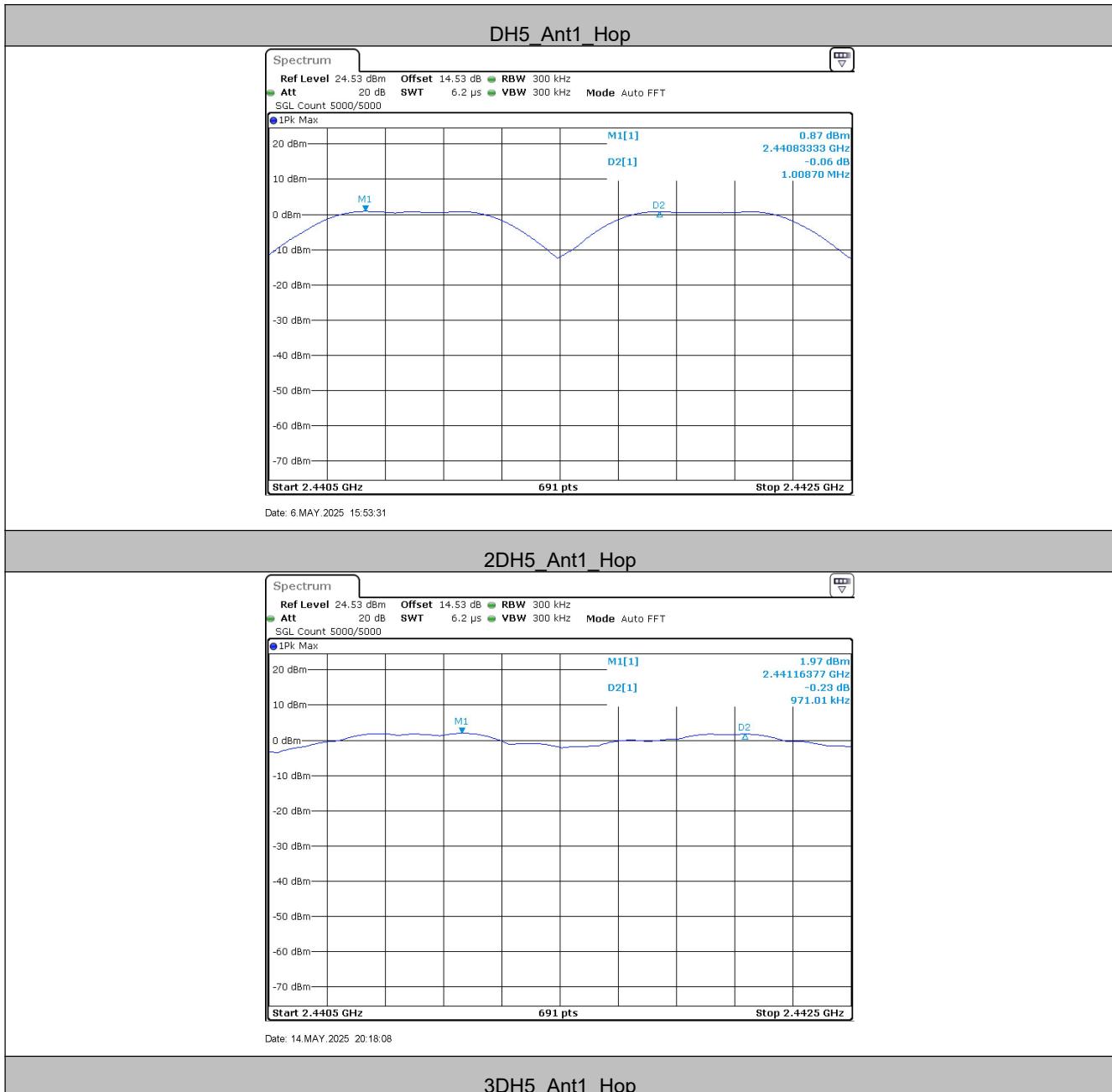
Test Requirement:	47 CFR Part 15C Section 15.247 (a)(1)
Test Method:	ANSI C63.10:2013
Test Setup:	 Remark: Offset=Cable loss+ attenuation factor.
Limit:	2/3 of the 20dB bandwidth Remark: the transmission power is less than 0.125W.
Exploratory Test Mode:	Hopping transmitting with all kind of modulation and all kind of data type
Final Test Mode:	Only the worst case is recorded in the report.
Test Results:	Pass

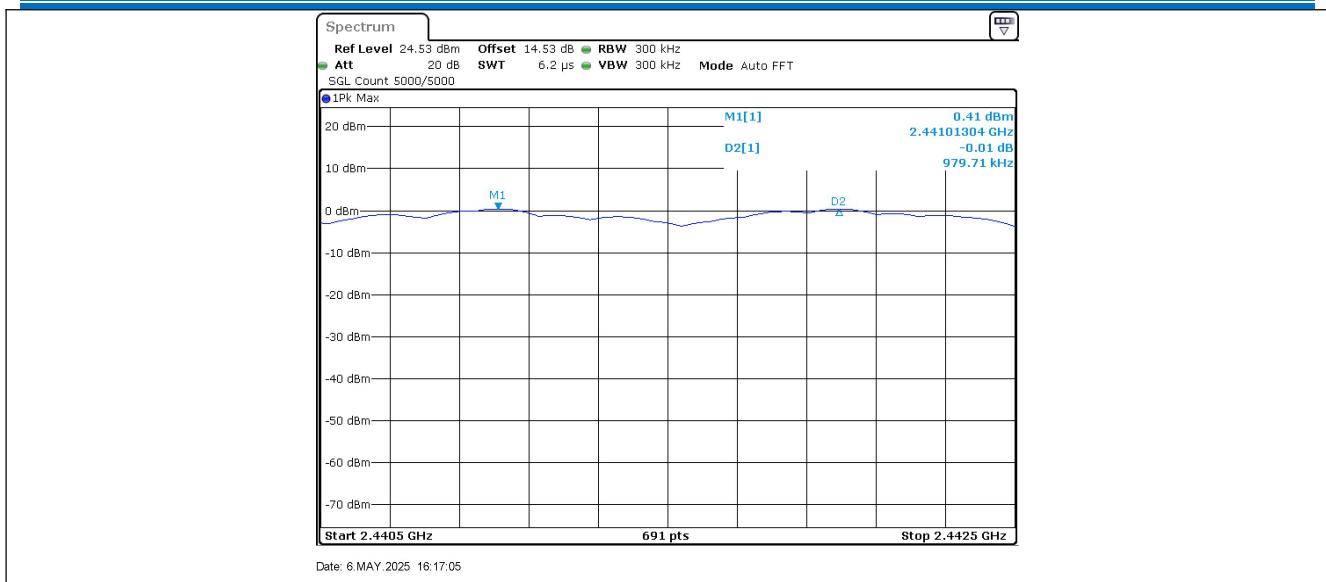
**Measurement Data**

TestMode	Freq(MHz)	Result[MHz]	Limit[MHz]	Verdict
DH5	Hop	1.009	≥0.64	PASS
2DH5	Hop	0.971	≥0.860	PASS
3DH5	Hop	0.98	≥0.867	PASS

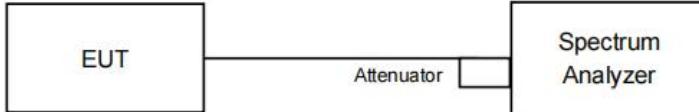
Mode	20dB bandwidth (MHz) (worse case)	Limit (MHz) (Carrier Frequencies Separation)
GFSK	0.96	≥0.64
π/4DQPSK	1.29	≥0.860
8DPSK	1.30	≥0.867

Test plot as follows:





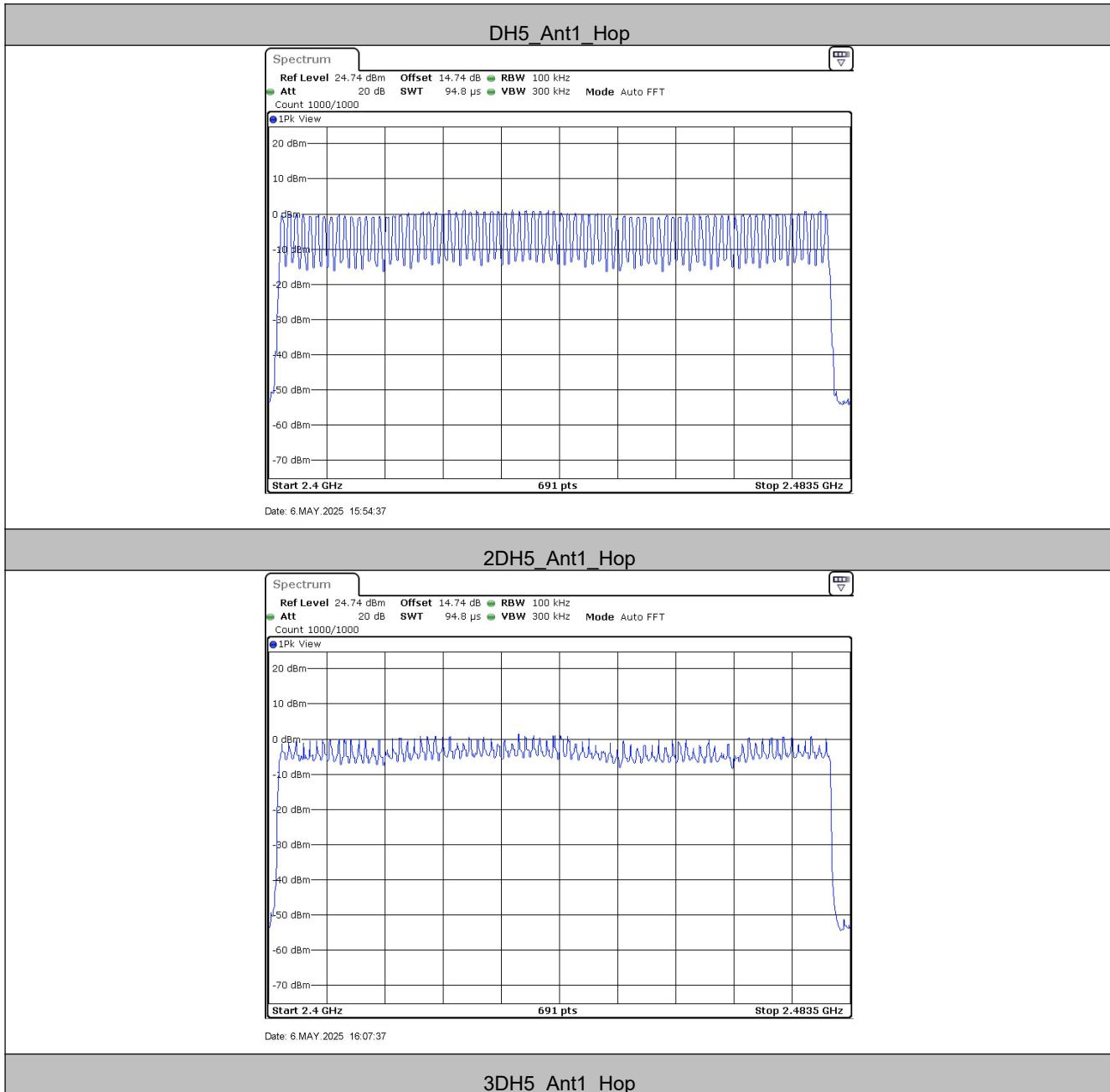
## 5.6 Hopping Channel Number

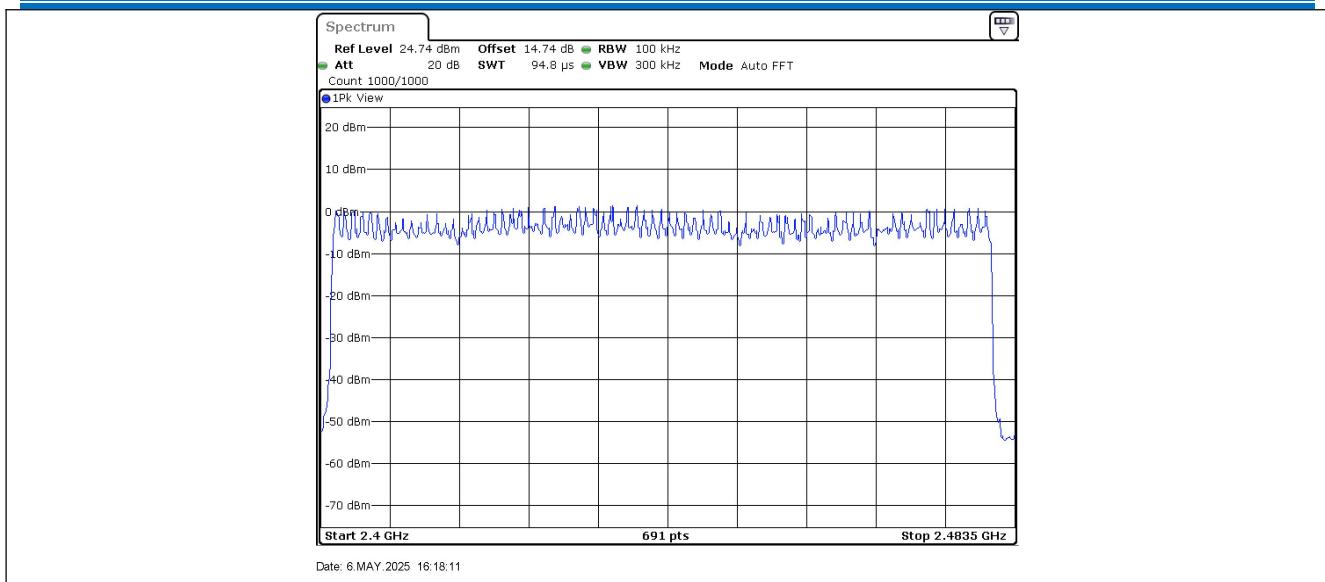
Test Requirement:	47 CFR Part 15C Section 15.247 (a)(1)	
Test Method:	ANSI C63.10:2013	
Test Setup:		<p><i>Remark: Offset=Cable loss+ attenuation factor.</i></p>
Limit:	At least 15 channels	
Exploratory Test Mode:	hopping transmitting with all kind of modulation and all kind of data type	
Final Test Mode:	Only the worst case is recorded in the report.	
Test Results:	Pass	

### Measurement Data

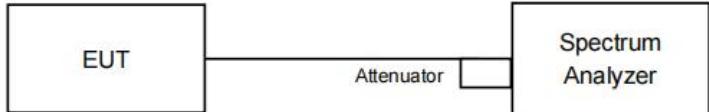
Mode	Hopping channel numbers	Limit
GFSK	79	≥15
π/4DQPSK	79	≥15
8DPSK	79	≥15

Test plot as follows:





## 5.7 Dwell Time

Test Requirement:	47 CFR Part 15C Section 15.247 (a)(1)
Test Method:	ANSI C63.10:2013
Test Setup:	 <p><i>Remark: Offset=Cable loss+ attenuation factor.</i></p>
Test Mode:	
Limit:	0.4 Second
Test Results:	Pass

**Measurement Data**

TestMode	Freq(MHz)	BurstWidth [ms]	TotalHops [Num]	Result[s]	Limit[s]	Verdict
DH1	Hop	0.379	320	0.121	$\leq 0.4$	PASS
DH3	Hop	1.628	170	0.277	$\leq 0.4$	PASS
DH5	Hop	2.868	130	0.373	$\leq 0.4$	PASS
2DH1	Hop	0.388	330	0.128	$\leq 0.4$	PASS
2DH3	Hop	1.631	170	0.277	$\leq 0.4$	PASS
2DH5	Hop	2.873	80	0.23	$\leq 0.4$	PASS
3DH1	Hop	0.388	320	0.124	$\leq 0.4$	PASS
3DH3	Hop	1.631	160	0.261	$\leq 0.4$	PASS
3DH5	Hop	2.874	130	0.374	$\leq 0.4$	PASS

**Remark:**

The test period:  $T = 0.4 \text{ Second/Channel} \times 79 \text{ Channel} = 31.6 \text{ s}$

**Test plot as follows:**

